Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/527,087	MAEKAWA ET AL.	
Examiner	Art Unit	

Brian Szmal

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Class	Subclass	Date	Examiner
600	546, 511	9/11/2007	BS
607	45	9/11/2007	BS
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INTERFERENCE SEARCHED				
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